

Metric Learning: Fundamentals, Applications and The state of the art

by
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Abstract: Metrics are everywhere in pattern recognition and machine learning; they are integral components of classification, clustering, ranking and retrieval approaches. In fact a good metric is often all you need for solving a given problem. Standard metrics such as L2 are almost always sub optimal, which is why a lot of effort has been dedicated in the past 2 decades to learn an optimal metric given a goal and some data. This talk will present the fundamentals of metric learning, explain how and why it transitioned from shallow to deep formulations, provide an insight into the latest developments along with numerous real-world applications.